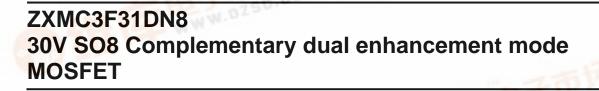
A Product Line of Diodes Incorporated



### Summary

Device	V <sub>(BR)DSS</sub> (V)	Q <sub>G</sub> (nC)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A)
Q1	30	12.9	0.024 @ V <sub>GS</sub> = 10V	7.3
S12 1	12.1-1		0.039 @ V <sub>GS</sub> = 4.5V	5.7
Q2	-30	12.7	0.045 @ V <sub>GS</sub> = -10V	5.3
			0.080 @ V <sub>GS</sub> = -4.5V	4

### Description

This new generation Trench MOSFET from Zetex has been designed to minimize the on-state resistance (R<sub>DS(on)</sub>) and yet maintain superior switching performance making it ideal for power management and battery charging functions.

### **Features**

- Low on-resistance
- 4.5V gate drive capability
- Low profile SOIC package •

### **Applications**

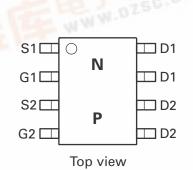
- **DC-DC Converters**
- SMPS
- Load switching switches
- Motor control
- Backlighting

### **Ordering information**

Device	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMC3F31DN8TA	7	12	500
Device marking	BE JUNN.	DZSC.COM	

### **Device marking**

ZXMC 3F31



G

**S2** 

**Q2 P-Channel** 

D1

**S1** 

Q1 N-Channel

G1





#### Absolute maximum ratings

Parameter	Symbol	N- channel Q1	P- channel Q2	Unit
Drain-Source voltage	V <sub>DSS</sub>	30	-30	V
Gate-Source voltage	V <sub>GS</sub>	±20	±20	V
Continuous Drain current @ $V_{GS}$ = 10V; $T_A$ =25°C (b)(d) @ $V_{GS}$ = 10V; $T_A$ =70°C (b)(d) @ $V_{GS}$ = 10V; $T_A$ =25°C (a)(d) (c)(c)	ID	7.3 5.9 5.7	5.3 4.3 4.1	A
(a)(e) (a)(b) (c) $V_{GS} = 10V; T_A = 25^{\circ}C$ (b)(c) (c) $V_{GS} = 10V; T_L = 25^{\circ}C$		6.8 7.8	4.9 5.7	
Pulsed Drain current <sup>(c)</sup>	I <sub>DM</sub>	33	23	А
Continuous Source current (Body diode) <sup>(b)(d)</sup>	۱ <sub>S</sub>	3.5	3.2	А
Pulsed Source current (Body diode) (c)(d)	I <sub>SM</sub>	33	23	А
Power dissipation at T <sub>A</sub> =25°C <sup>(a)(d)</sup> Linear derating factor	P <sub>D</sub>		25 0	W mW/°C
Power dissipation at T <sub>A</sub> =25°C <sup>(a)(e)</sup> Linear derating factor	PD		.8 4	W mW/°C
Power dissipation at $T_A = 25^{\circ}C^{(b)(d)}$ Linear derating factor	PD		.1 7	W mW/°C
Power dissipation at $T_L = 25^{\circ}C^{(f) (d)}$ Linear derating factor	PD		35 9	W mW/°C
Operating and storage temperature range	Tj, T <sub>stg</sub>	-55 te	o 150	°C

### **Thermal resistance**

Parameter	Symbol	Value	Unit
Junction to ambient <sup>(a)(d)</sup>	$R_{\theta JA}$	100	°C/W
Junction to ambient <sup>(a)(e)</sup>	R <sub>0JA</sub>	70	°C/W
Junction to ambient <sup>(b)(d)</sup>	R <sub>0JA</sub>	60	°C/W
Junction to lead <sup>(f)</sup> (d)	R <sub>θJL</sub>	53	°C/W

NOTES:

(a) For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 2oz copper, in still air conditions.

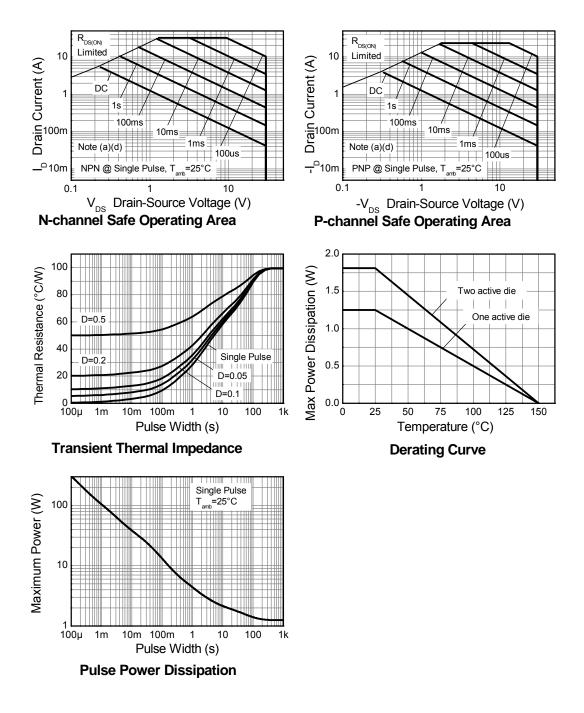
(b) Mounted on FR4 PCB measured at t  $\leq$  10 sec.

(c) Repetitive rating on 25mm x 25mm FR4 PCB, D=0.02, pulse width 300us – pulse width limited by maximum junction temperature.

(d) For a device with one active die.

(e) For a device with two active die running at equal power.
(f) Thermal resistance from junction to solder-point (at the end of the drain lead).

#### **Thermal characteristics**



Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static			•	•		
Drain-Source breakdown voltage	V <sub>(BR)DSS</sub>	30			V	$I_{D}$ = 250µA, V <sub>GS</sub> =0V
Zero Gate voltage Drain current	I <sub>DSS</sub>			0.5	μA	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V
Gate-Body leakage	I <sub>GSS</sub>			100	nA	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V
Gate-Source threshold voltage	V <sub>GS(th)</sub>	1.0		3.0	V	$I_D$ = 250 $\mu$ A, $V_{DS}$ = $V_{GS}$
Static Drain-Source on-state resistance <sup>(*)</sup>	R <sub>DS(on)</sub>			0.024 0.039	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 7.0A V <sub>GS</sub> = 4.5, I <sub>D</sub> = 6.0A
Forward Transconductance <sup>(*) (†)</sup>	9 <sub>fs</sub>		16.5		S	V <sub>DS</sub> = 15V, I <sub>D</sub> = 7.0A
Dynamic <sup>(†)</sup>						
Input capacitance	C <sub>iss</sub>		608		pF	
Output capacitance	C <sub>oss</sub>		132		pF	V <sub>DS</sub> = 15V, V <sub>GS</sub> =0V
Reverse transfer capacitance	C <sub>rss</sub>		72		pF	f=1MHz
Switching <sup>(‡) (†)</sup>					•	
Turn-on-delay time	t <sub>d(on)</sub>		2.9		ns	
Rise time	t <sub>r</sub>		3.3		ns	V <sub>DD</sub> = 15V, V <sub>GS</sub> =10V
Turn-off delay time	t <sub>d(off)</sub>		16		ns	I <sub>D</sub> = 1A
Fall time	t <sub>f</sub>		8		ns	R <sub>G</sub> ≅ 6.0Ω,
Total Gate charge	Qg		12.9		nC	
Gate-Source charge	Q <sub>gs</sub>		2.5		nC	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V
Gate-Drain charge	Q <sub>gd</sub>		2.52		nC	I <sub>D</sub> = 7A
Source-Drain diode	<u>, -</u>			1	1	
Diode forward voltage <sup>(*)</sup>	V <sub>SD</sub>		0.82	1.2	V	I <sub>S</sub> = 1.7A,V <sub>GS</sub> =0V
Reverse recovery time (‡)	t <sub>rr</sub>		12		ns	I <sub>S</sub> = 2.2A,di/dt=100A/μs
Reverse recovery charge <sup>(‡)</sup>	Q <sub>rr</sub>		4.8		nC	15- 2.2Λ,0001-100Λ/μS

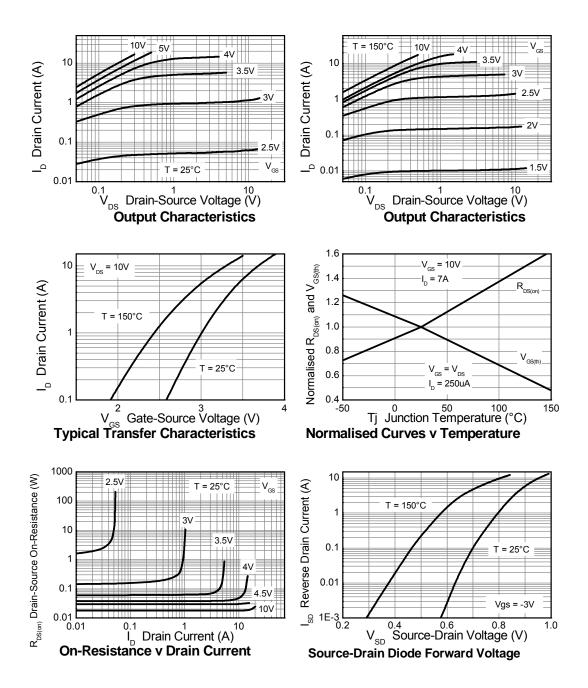
### Q1 N-channel electrical characteristics (at $T_{amb} = 25^{\circ}C$ unless otherwise stated)

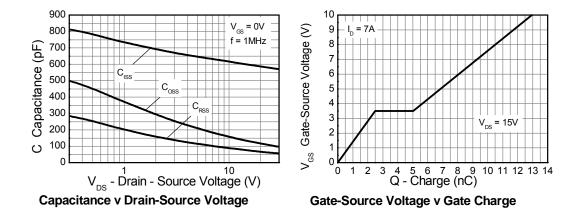
#### NOTES:

(\*) Measured under pulsed conditions. Pulse width  $\leq 300 \mu s;$  duty cycle  $\leq 2\%.$ 

(†)Switching characteristics are independent of operating junction temperature.
 (‡)For design aid only, not subject to production testing

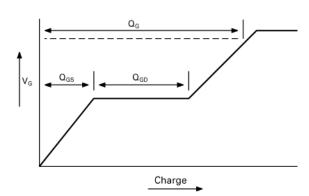
### Q1 Typical characteristics



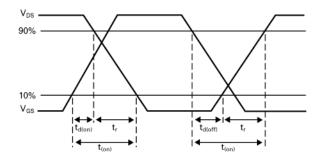


### Q1 Typical characteristics –cntd.

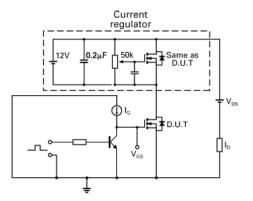
**Test circuits** 



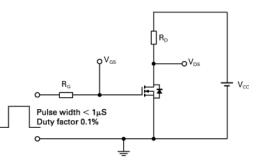
Basic gate charge waveform



Switching time waveforms



Gate charge test circuit





Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static						
Drain-Source breakdown voltage	V <sub>(BR)DSS</sub>	-30			V	$I_{D}$ = -250µA, $V_{GS}$ =0V
Zero Gate voltage Drain current	I <sub>DSS</sub>			-5.0	μA	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0V
Gate-Body leakage	I <sub>GSS</sub>			-100	nA	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V
Gate-Source threshold voltage	V <sub>GS(th)</sub>	-1.0		-3.0	V	$I_D$ = -250 $\mu$ A, $V_{DS}$ = $V_{GS}$
Static Drain-Source on-state resistance <sup>(*)</sup>	R <sub>DS(on)</sub>			0.045 0.080	Ω	V <sub>GS</sub> = -10V, I <sub>D</sub> = -5.0A V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -4.0A
Forward Transconductance <sup>(*) (†)</sup>	9 <sub>fs</sub>		14		S	V <sub>DS</sub> = -15V, I <sub>D</sub> = -5.0A
Dynamic <sup>(†)</sup>						
Input capacitance	C <sub>iss</sub>		670		pF	
Output capacitance	C <sub>oss</sub>		126		pF	V <sub>DS</sub> = -15V, V <sub>GS</sub> =0V
Reverse transfer capacitance	C <sub>rss</sub>		70		pF	f=1MHz
Switching <sup>(‡) (†)</sup>						
Turn-on-delay time	t <sub>d(on)</sub>		1.9		ns	
Rise time	t <sub>r</sub>		3		ns	V <sub>DD</sub> = -15V, V <sub>GS</sub> =-10V
Turn-off delay time	t <sub>d(off)</sub>		30		ns	I <sub>D</sub> = -1A
Fall time	t <sub>f</sub>		21		ns	R <sub>G</sub> ≅ 6.0Ω,
Total Gate charge	Qg		12.7		nC	
Gate-Source charge	Q <sub>gs</sub>		2		nC	V <sub>DS</sub> = -15V, V <sub>GS</sub> = -10V
Gate-Drain charge	Q <sub>gd</sub>		2.4		nC	I <sub>D</sub> = -5A
Source-Drain diode						
Diode forward voltage <sup>(*)</sup>	V <sub>SD</sub>		-0.82	-1.2	V	I <sub>S</sub> = -2A,V <sub>GS</sub> =0V
Reverse recovery time $^{(\ddagger)}$	t <sub>rr</sub>		16.5		ns	I <sub>S</sub> = -2.1A,di/dt=100A/μs
Reverse recovery charge <sup>(‡)</sup>	Q <sub>rr</sub>		11.5		nC	15 2.1Α,αι/αι-100Α/μδ

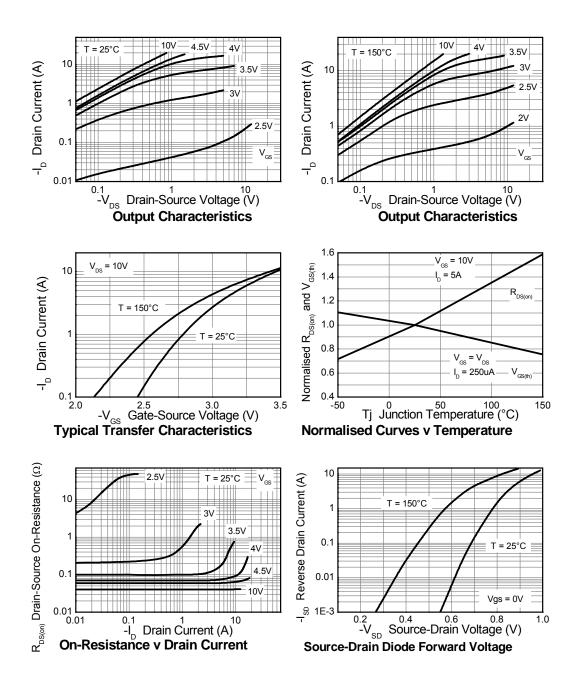
### Q2 P-channel electrical characteristics (at $T_{amb} = 25^{\circ}C$ unless otherwise stated)

#### NOTES:

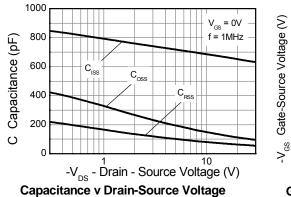
(\*) Measured under pulsed conditions. Pulse width  $\leq$  300µs; duty cycle  $\leq$  2%. (†)Switching characteristics are independent of operating junction temperature.

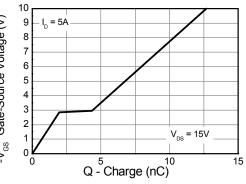
(‡)For design aid only, not subject to production testing

### **Typical characteristics**



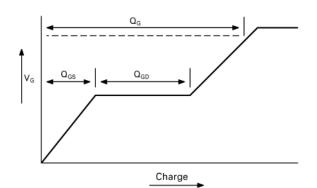
### **Typical characteristics**



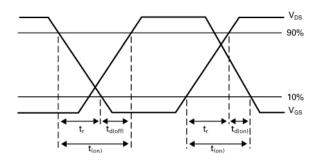




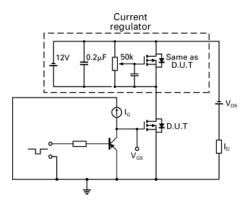
**Test circuits** 



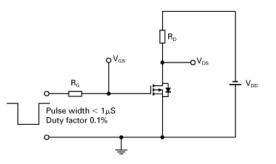
Basic gate charge waveform



Switching time waveforms

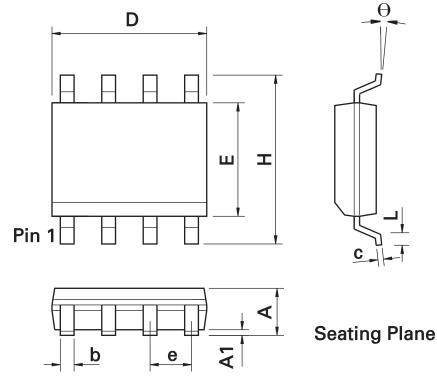


Gate charge test circuit



### Switching time test circuit

### Package outline SO8



**SO8 Package Information** 

DIM	Inc	hes	Millin	neters	DIM	Inc	hes	Millim	neters
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
А	0.053	0.069	1.35	1.75	е	0.050	BSC	1.27	BSC
A1	0.004	0.010	0.10	0.25	b	0.013	0.020	0.33	0.51
D	0.189	0.197	4.80	5.00	с	0.008	0.010	0.19	0.25
н	0.228	0.244	5.80	6.20	U	0°	8°	0°	8°
E	0.150	0.157	3.80	4.00	h	0.010	0.020	0.25	0.50
L	0.016	0.050	0.40	1.27	-	-	-	-	-

Note: Controlling dimensions are in inches. Approximate dimensions are provided in millimeters

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- 1. are intended to implant into the body
- or

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- 2. support or sustain life and whose failure to perform when properly used in accordance with instructions
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"Active"	Product status recommended	for new designs	
"Last time buy (LTB)"	Device will be discontinued ar	nd last time buy period and deliver	ry is in effect
"Not recommended for new dea	signs" Device is still in production to	support existing designs and prod	luction
"Obsolete"	Production has been discontin	nued	
Datasheet status key:			
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		je in any manner without notice.	
"Provisional version"	This term denotes a pre-relea	se datasheet. It provides a clear in	ndication of anticipated performance.
	However, changes to the test	conditions and specifications may	occur, at any time and without notice
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